


<b>Search Notes</b>  	<b>Application/Control No.</b>  10516818	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA ET AL.
	<b>Examiner</b>  David M Naff	<b>Art Unit</b>  1657

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
West-see search history	8/1/08	DMN
West-see search history	1/19/09	DMN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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